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Gate oxide scaling limits and projection - group of 2 »

C Hu - Electron Devices Meeting, 1996., International, 1996 - [ieeexplore.ieee.org](#)
 ... defects, plasma process damage, mobility **degradation**, poly-gate ... generally but not
 always raises **circuit** speed. ... tolerant of the same current **stress** than thicker ...
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Influence of thermal stress on IV characteristics and low-frequency noise of AlGaInP UHB-LEDs

J Berntgen, T Lieske, B Schineller, M Deufel, M ... - Indium Phosphide and Related
 Materials, 1998 International ..., 1998 - [ieeexplore.ieee.org](#)
 ... to get information about the **degradation** mechanisms inside ... This **stress** dependent
 change of the IV curves can be modeled by the equivalent **circuit** diagram shown ...
[Related Articles](#) - [Web Search](#)

Self-localization of degradation process in pre-breakdown stage of thin SiO₂ films: new model and ...

AE Kotov, K NOVA - Nonvolatile Memory Technology Conference, 1996., Sixth ..., 1996 -
[ieeexplore.ieee.org](#)
 ... during the entire stage of **degradation**, 2) when ... quantum yield of impact ionization,
 13+A3 **Stress** time charge ... Considering the capacitance equivalent **circuit** of T ...
[Related Articles](#) - [Web Search](#)

Hot electron effects and degradation of GaAs and InP HEMTs for microwave and millimetre-wave ... - group of 5 »

R Menozzi - Semicond. Sci. Technol, 1998 - [iop.org](#)
 ... techniques, to device and **circuit** processing and ... featured temperature-accelerated
stress experiments, thus ... to thermally activated **degradation** mechanisms, such ...
 Cited by 7 - [Related Articles](#) - [Web Search](#) - [BL Direct](#)

SURFACE MICROMACHINED, DIGITALLY FORCE-BALANCED ACCELEROMETER

B Sensor, A Center - [ieeexplore.ieee.org](#)
 ... will not have any noticeable **degradation** for temperatures ... the drift, and package
 induced **stress** are common mode ... The detection **circuit** is located in the middle ...
[Related Articles](#) - [Web Search](#)

Quality assessment of speech coding and speech synthesis systems - group of 2 »

N Kitawaki, H Nagabuchi - Communications Magazine, IEEE, 1988 - [ieeexplore.ieee.org](#)
 ... T) implies the degree of **degradation** by transmission ... The quality of the test **circuit**
 is defined as the ... Phonetic Balance (PB), word length, **stress** position, word ...
 Cited by 12 - [Related Articles](#) - [Web Search](#)

A 1.95-V, 0.34-mW, 12-b sigma-delta modulator stabilized by local feedback loops - group of 2 »

S Au, BH Leung - Solid-State Circuits, IEEE Journal of, 1997 - [ieeexplore.ieee.org](#)
 ... means higher **stress** for the thin oxide in fine ... The scaled-down clock booster **circuit**
 is also used to ... based, does not show significant SNR **degradation** until the op ...

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Impact of epi facets on deep submicron elevated source/drain

MOSFET characteristics - group of 2 »

JJ Sun, CM Osburn - Electron Devices, IEEE Transactions on, 1998 - [ieeexplore.ieee.org](#)

... the effect of Miller capacitance on **circuit speed** ... A slight **degradation** of drain-induced-barrier- lowering ... Channel MOS Transistors During Channel-Hot-Hole **Stress** ...

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Digital and Analog Communication Systems K. Sam Shanmugam

RE Ziemer - [ieeexplore.ieee.org](#)

... some knowledge of **circuit** analysis and linear system ... Silver- man (motion and noise **degradation**), Nahi, Woods ... Several authors **stress** line- / by-line techniques ...

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AN OVERVIEW OF VARIABLE RATE SPEECH CODING FOR CELLULAR NETWORKS

A Gersho, E Paksoy - [ieeexplore.ieee.org](#)

... was studied by Chou and Lookabaugh [7] where joint optimization of vector **quantization** and entropy coding ... Often, the **degradation** in reproduced speech is caused

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